

# TECHNICAL REPORT

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## Road vehicles — Application of predictive maintenance to hardware with ISO 26262-5

*Véhicules routiers — Application de la maintenance prédictive au  
matériel à l'aide de l'ISO 26262-5*



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# Contents

	Page
<b>Foreword</b>	<b>iv</b>
<b>Introduction</b>	<b>v</b>
<b>1 Scope</b>	<b>1</b>
<b>2 Normative references</b>	<b>1</b>
<b>3 Terms and definitions</b>	<b>1</b>
<b>4 Abbreviated terms</b>	<b>2</b>
<b>5 Literature survey of degrading faults</b>	<b>4</b>
5.1 General	4
5.2 Degrading faults in industry standards	4
5.2.1 JEDEC JEP122H <sup>[4]</sup>	4
5.3 Degrading faults in technical publications	5
5.3.1 Advanced CMOS Reliability Update: Sub 20 nm FinFET Assessment <sup>[5]</sup>	5
5.3.2 Circuit-Based Reliability Consideration in FinFET Technology <sup>[6]</sup>	6
5.3.3 Intermittent Faults and Effects on Reliability of Integrated Circuits <sup>[7]</sup>	6
<b>6 Literature survey on predictive maintenance</b>	<b>6</b>
6.1 General	6
6.2 Predictive maintenance in industry standards	6
6.2.1 IEC 61508 <sup>[9]</sup>	6
6.2.2 IEEE Std 1856 <sup>[3]</sup>	6
6.3 Predictive maintenance in technical publications	7
6.3.1 A Survey of Online Failure Prediction Methods <sup>[10]</sup>	7
6.3.2 An Odometer for CPUs <sup>[11]</sup>	7
6.3.3 Circuit Failure Prediction for Robust System Design in Scaled CMOS <sup>[12]</sup>	8
6.3.4 A Circuit Failure Prediction Mechanism (DART) for High Field Reliability <sup>[13]</sup>	8
6.3.5 Predicting Remediations for Hardware Failures in Large-Scale Datacenters <sup>[14]</sup>	8
6.3.6 Improving Analog Functional Safety Using Data-Driven Anomaly Detection <sup>[15]</sup>	8
<b>7 Degrading faults and the ISO 26262 series</b>	<b>8</b>
7.1 Understanding the lifecycle of degrading faults	8
7.2 Classification of degrading faults	12
7.3 Quantifying degrading fault base failure rate	12
7.3.1 Industry standards and models	12
7.3.2 Field data	13
7.3.3 Expert judgement	13
<b>8 Applying predictive maintenance</b>	<b>13</b>
8.1 Diagnostic coverage (DC) evaluation for predictive mechanisms	13
8.2 Considering random hardware metrics	13
8.2.1 Impacting the SPFM and LFM	13
8.2.2 Application as a dedicated measure	14
8.3 Considering RUL prediction	14
<b>Annex A (informative) An approach to handling degrading faults</b>	<b>16</b>
<b>Bibliography</b>	<b>18</b>